LZ2324AK 1/3 type B/W CCD Area Sensor for CCIR

DESCRIPTION

LZ2324AK is a 1/3-type (6.0 mm) solid-state image sensor that consists of PN phote-diodes and CCDs (charge-coupled devices). Having approximately0900pixels (horizontal 542 x vertical 582), the sensor provides a high resolution stable B/W image.

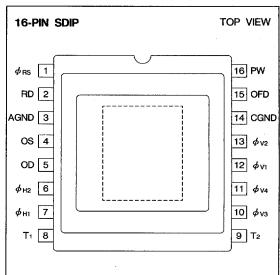
FEATURES

 Number of pixels : 512 (H)×582 (V) Pixel pitch : 9.6 μ m (H)×6.3 μ m (V) Number of optical black pixels

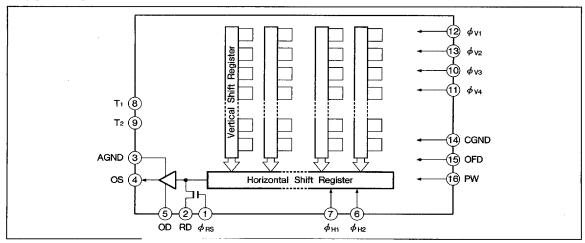
: Horizontal; front 2 and rear 28

- Low fixed pattern noise and lag
- No sticking and no image distortion
- Blooming suppression structure
- Built-in output amplifier
- Variable electronic shutter (1/50 to 1/10 000 s)
- Compatible with CCIR standard
- Package: 16-pin SDIP[CERDIP](WDIP016-N-0500C)

PIN CONNECTIONS



BLOCK DIAGRAM



8180798 0013689 976

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PIN DESCRIPTION

| SYMBOL | PIN NAME |
|--|--------------------------------------|
| RD | Reset transistor drain |
| OD | Output transistor drain |
| os | Video output |
| φ _{RS} | Reset transistor gate clock |
| $\phi_{V1}, \phi_{V2}, \phi_{V3}, \phi_{V4}$ | Vertical shift register gate clock |
| Фн1, Фн2 | Horizontal shift register gate clock |
| OFD | Overflow drain |
| PW | P type well |
| AGND | Analog part ground |
| CGND | Clock part ground |
| T1, T2 | Test terminal |

ABSOLUTE MAXIMUM RATINGS

(Ta=25°C)

| PARAMETER | SYMBOL | RATING | UNIT |
|--|-----------------|-------------|------|
| Output transistor drain voltage | V od | 0 to +18 | V |
| Reset transistor drain voltage | VRD | 0 to +18 | ٧ |
| Overflow drain voltage | V OFD | 0 to +55 | V |
| Test terminal, T ₁ | V _{T1} | 0 to +18 | V |
| Test terminal, T2 | V T2 | -0.3 to +18 | ٧ |
| Reset gate clock voltage | V ¢ RS | -0.3 to +18 | V |
| Vertical shift register clock voltage | Vøv | -9.0 to +18 | V |
| Horizontal shift register clock voltage | Vøн | -0.3 to +18 | V |
| Voltage difference between PW and vertical clock | Vpw-Vøv | -27 to 0 | V |
| Storage temperature | Tstg | -20 to +80 | °C |
| Operating ambient temperature | Topr | -20 to +70 | °C |

RECOMMENDED OPERATING CONDITIONS

| | PARAME | TER | SYMBOL | MIN. TYP. MAX. UI | | UNIT | NOTE | |
|---|---|--------------------------|--------------------------------------|-------------------|------|------------------|------|---|
| Operating ambient temperature | | Topr | | 25.0 | | °C | | |
| Output transistor drain voltage | | Vod | 14.5 | 15.0 | 16.0 | V | | |
| Reset transistor drain voltage | | VRD | | Vod | | ٧ | | |
| Overflow | When DC is applied | | Vofd | 5.0 | | 19.0 | ٧ | 1 |
| drain voltage | When pulse is applied p-p level | | V ¢ OFD | 22.0 | | | ٧ | 2 |
| Analog part | ground | | AGND | | 0.0 | | ٧ | |
| Clock part of | ground | | CGND | | 0.0 | | ٧ | |
| P-well voltag | P-well voltage | | Vew | -9.0 | | VφVL | V | |
| Test termina | Test terminal, T1 | | VT1 | | Vod | | V | |
| Test termina | nl, T2 | | V T2 | | 0.0 | | ٧ | |
| Vertical shift register clock | | LOW level | VφV1L, VφV2L VφV3L, VφV4L | -8.5 | -8.0 | -7.5 | ν | |
| | | INTERMEDIATE level | V φ V11, V φ V21 V φ V31, V φ V41 | | 0.0 | | ٧ | |
| | | HIGH level | V ФV1Н, V ФV3Н | 16.0 | 16.5 | 17.0 | ٧ | |
| Horizontal shift | | LOW level | V φ Η1L, V φ Η2L | -0.05 | 0.0 | 0.05 | ٧ | |
| register clock | k | HIGH level | V ф Н1Н, V ф Н2Н | 4.7 | 5.0 | 6.0 | ٧ | |
| Poset sets sleek | | LOW level | V ¢ RSL | 0.0 | | V RD-12.0 | ٧ | |
| Reset gate clock | CIOCK | HIGH level | V ¢ RSH | VRD - 7.5 | _ | 9.5 | ٧ | |
| Vertical shift register clock frequency | | fφV1, fφV2 fφV3, fφV4 | | 15.63 | | kHz | | |
| Horizontal sl | Horizontal shift register clock frequency | | fφH1, fφH2 | | 9.66 | | MHz | |
| Reset gate clock frequency | | føRS | | 9.66 | | MHz | | |

NOTES:

- 1. When DC voltage is applied, shutter speed is 1/50 seconds.
- 2. When pulse is applied, shutter speed is less than 1/50 seconds.

ELECTRICAL CHARACTERISTICS (Drive method : Field Accumulation)

 $(T=25^{\circ}\text{C}, \text{ Operating conditions}: \text{ typical values for the recommended operating conditions, Color temperature of light source: 3200 K / IR cut-off filter (CM-500, 1 mmt))$

| PARAMETER | SYMBOL | MIN. | TYP. | MAX. | UNIT | NOTE |
|---------------------------------|--------|------|-------|-------|------|------|
| Photo response non-uniformity | PRNU | | | 10 | % | 2 |
| Saturation signal | Vsat | 550 | | | mV | 3 |
| Saturation non-uniformity | SSUN | | | 20 | % | 4 |
| Dark output voltage | Vdark | | 0.3 | 3.0 | mV | 1, 5 |
| Dark signal non-uniformity | DSNU | | 0.6 | 2.0 | mV | 1, 6 |
| Sensitivity | R | 360 | 500 | | mV | 7 |
| Gamma | γ | | 1 | | | |
| Smear ratio | SMR | | 0.009 | 0.016 | % | 8 |
| Image lag | Al | | | 1.0 | % | 9 |
| Blooming suppression ratio | ABL | 1000 | | | | 10 |
| Output transistor drain current | lop | | 4.0 | 8.0 | mA | |
| Output impedance | Ro | | 300 | | Ω | |
| Dark noise | Vnoise | | 0.2 | 0.4 | mV | 11 |
| OB difference in level | | | | 1.0 | mV | 12 |

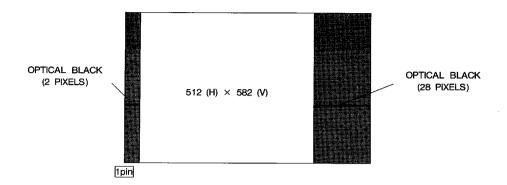
- The standard output voltage is defined as 150 mV by the average output voltage under uniform illumination.
- The standard exposure level is defined when the average output voltage is 150 mV under uniform illumination.

NOTES:

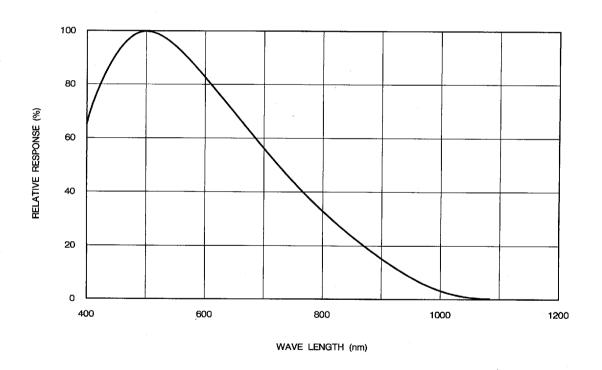
- 1. Ta: +60°C
- 2. The image area is divided into 10×10 segments. The segment's voltage is the average output voltage of all the pixels within the segment. PRNU is defined by (Vmax Vmin)/Vo, where Vmax and Vmin are the maximum and the minimum values of each segment's voltage respectively, when the average output voltage Vo is 150 mV.
- 3. The image area is divided into 10×10 segments. The saturation signal is defined as the minimum of each segment's voltage which is the average output voltage of all the pixels within the segment, when the exposure level is set as 10 times, compared to standard level.
- 4. The image area is divided into 10×10 segments. The voltage of a segment is the saturation signal (Vs), when the exposure level is set as 10 times, compared to standard level. SSUN is defined by (Vmax-Vmin)/Vs, when Vmax and Vmin are the maximum and minimum values of each segment's voltage respectively.
- 5. The average output voltage under a non-exposure condition.
- 6. The image area is divided into 10×10 segments. DSNU is defined by (Vdmax Vdmin) under the non-exposure con-

- dition where Vdmax and Vdmin are the maximum and the minimum values of each segment's voltage, respectively, that is the average output voltage over all pixels in the segment.
- The average output voltage when a 1000 lux light source attached with a 90% reflector is imaged by a lens of F4, f50 mm
- 8. The sensor is adjusted to position a V/10 square at the center of image area where V is the vertical length of the image area. SMR is defined by the ratio of the output voltage detected during the vertical blanking period to the maximum of the pixel voltage in the V/10 square.
- The sensor is exposed at the exposure level corresponding to the standard condition preceding non-exposure condition. Al is defined by the ratio between the output voltage measured at the 1st field during the non-exposure period and the standard output voltage.
- 10. The sensor is adjusted to position a V/10 square at the center of image area. ABL is the ratio between the exposure at the standard condition and the exposure at a point where a blooming is observed.
- 11. The RMS value of the dark noise (after CDS). The bandwidth range is from 100 kHz to 5.0 MHz.
- The difference between the average output voltage of the effective area and the OB part under the non-exposure condition

PIXEL STRUCTURE



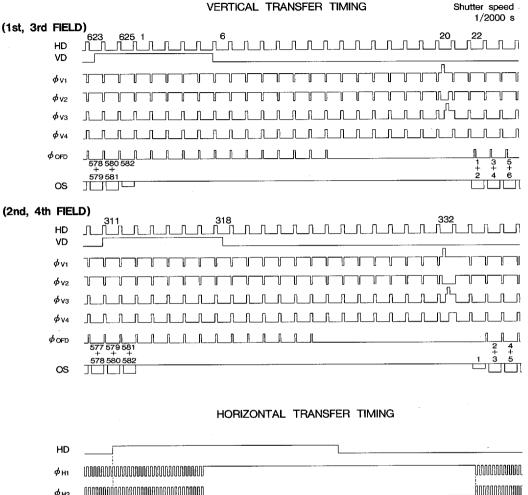
SPECTRAL RESPONSE EXAMPLE

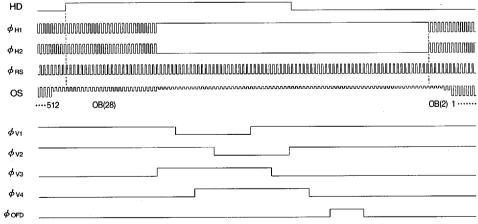


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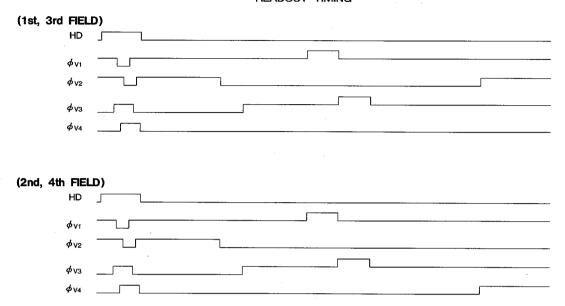
TIMING DIAGRAM EXAMPLE





■ 8180798 DO13694 233 **■**

READOUT TIMING



SYSTEM CONFIGURATION EXAMPLE

